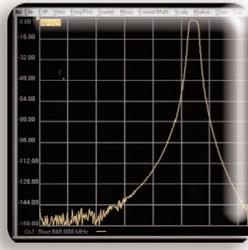
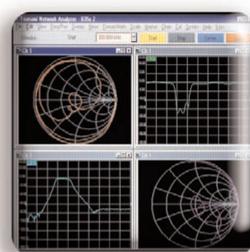
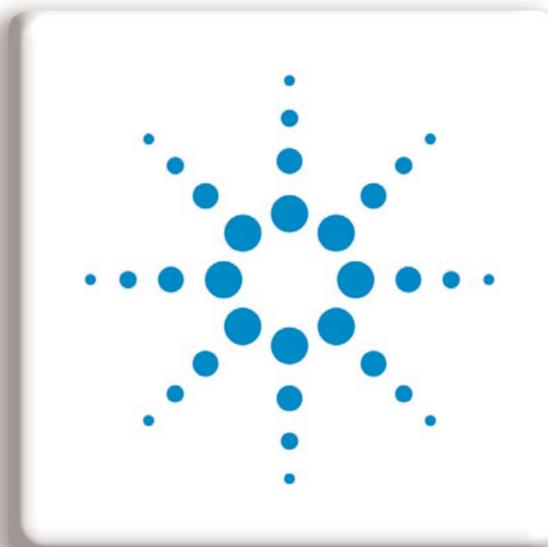
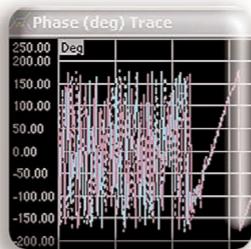
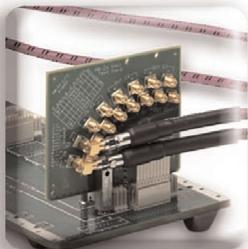


Agilent

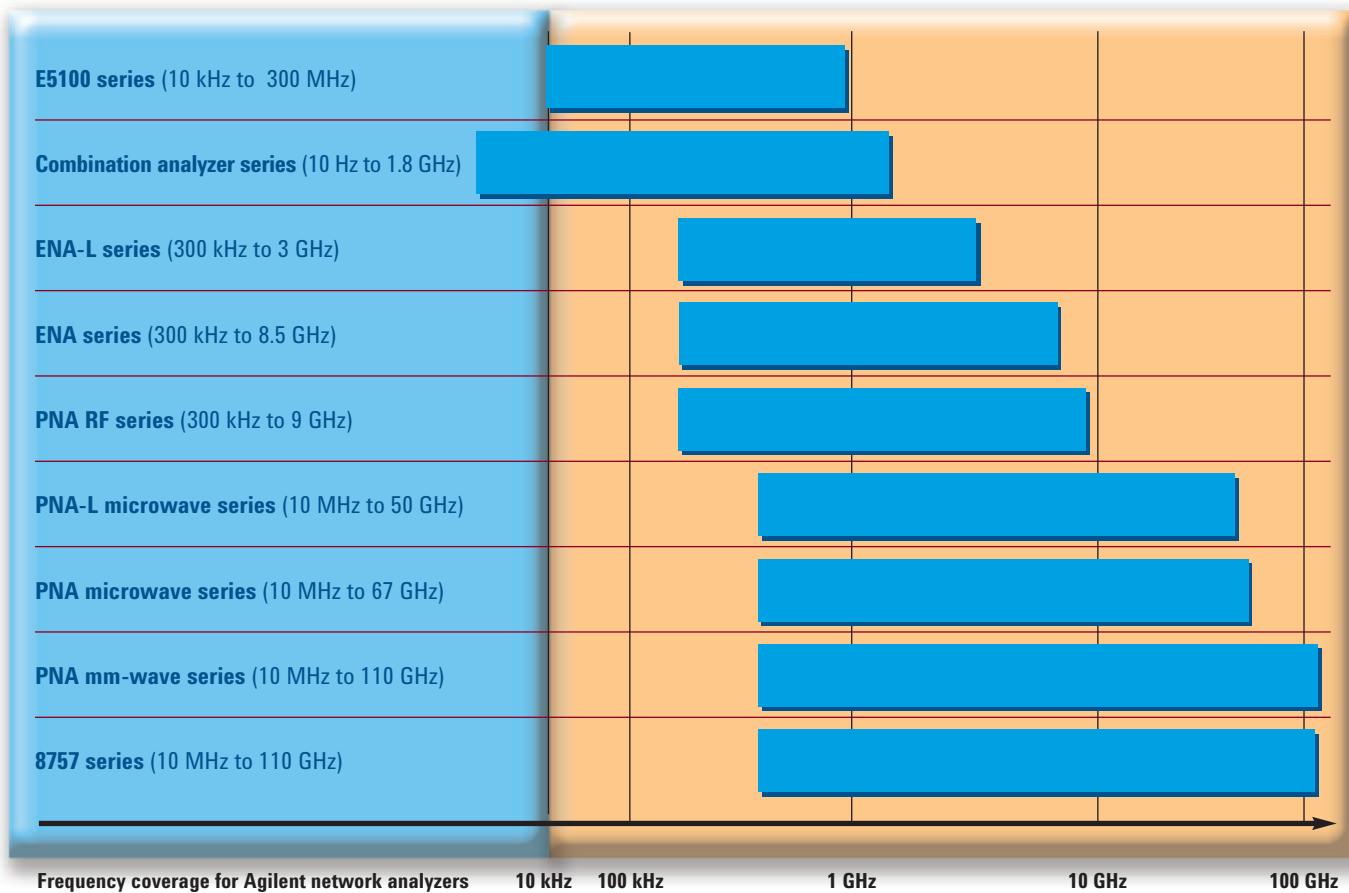
Network Analyzer Selection Guide



Agilent Technologies

Network Analyzers to Meet Your Needs

Agilent offers a variety of network analyzers with the frequency, performance, and versatility to meet your measurement needs. To help you determine which network analyzer is right for you, this selection guide provides an overview and side-by-side comparison of all our network analyzers. In addition, you will find a discussion of the typical network analyzer applications, the measurement needs of each, and how Agilent network analyzers meet those needs.



NOTE: The 8510 and the 871x network analyzers have been discontinued.
Although not listed here, the 872x and the 8753 network analyzers are still available for purchase.
For more information about these products, visit www.agilent.com/find/na.

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Information resources

High Throughput for Filter and Resonator Testing

E5100 network analyzers

E5100A

The Agilent E5100 network analyzer has a frequency range of 10 kHz to 300 MHz and is best fit for production line testing of crystal/ ceramic filters and resonators, as well as other electronic components, where very high test throughput is required.

The E5100A improves manufacturing efficiency by providing exceptionally fast measurement capabilities (up to 0.04 ms/point), built-in waveform analysis commands, and a part-handler interface.

The E5100A provides versatile analysis capabilities to fit your requirements for better yield and higher productivity throughout your entire manufacturing test process. The E5100A realizes high quality and high-speed tests with its fine IF bandwidth (IFBW) selection and low-noise circuitry. Convenient analysis and processing functions improve your productivity; especially in final test.



Features

- 0.04 ms/point measurement speed
- handler interface for mass-production
- filter and resonator waveform analysis commands

www.agilent.com/find/e5100

Network, Spectrum, and Impedance Analyzers in One Box

Combination analyzer series

4395A, 4396B

The Agilent combination analyzer series merges three analyzer functions into one powerful instrument: a vector network analyzer, a spectrum analyzer, and an optional impedance analyzer. The combination analyzer makes no compromise between vector-network, spectrum, and impedance performance. Use one analyzer for multiple testing needs when you want high speed and accuracy. Save equipment cost and bench space, while avoiding time-consuming, awkward cable hook-up to multiple instruments.

The Agilent 4395A/96B provides excellent LF/RF measurements for lab and production applications. In the lab, evaluate your designs completely and accurately with one instrument. Reduce test time with precise measurements and improved efficiency. On the production line, increase your throughput with the 4395A/96B by quickly and easily switching between different measurement types or tests. The 4395A/96B are breakthroughs in test instruments, delivering outstanding performance at an attractive price.



Features

- network, spectrum and optional impedance analysis
- fast narrowband spectrum measurement
- time-gated spectrum analysis option

www.agilent.com/find/combo

New Standard for Low-Cost Basic RF Network Analysis!

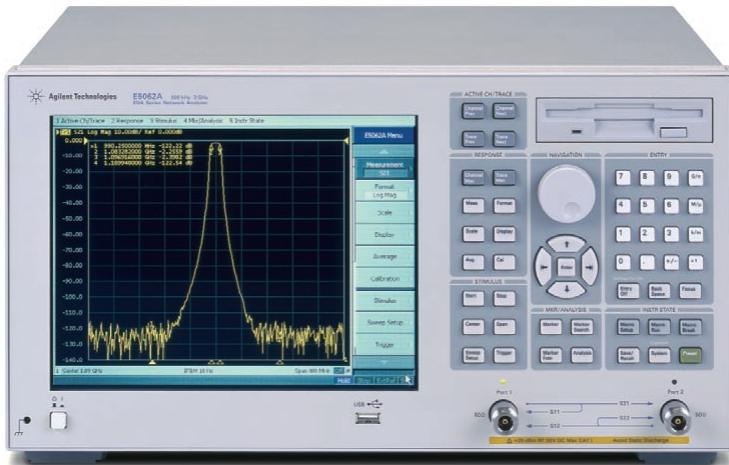
ENA-L RF network analyzers

E5061A, E5062A

Providing the latest in modern technology and flexibility, the Agilent ENA-L network analyzers provide basic vector network analysis in a wide range of industries and applications such as wireless communication, cable TV, automotive, education, and more. Designed to reduce tune and test times, these analyzers provide increased throughput to improve your measurement productivity.

The ENA-L offers all of the critical performance and features needed in R&D, manufacturing, and service to test RF components such as: filters, amplifiers, antennas, cables, CATV taps, and distribution amplifiers.

The affordably priced ENA-L, equipped with the core functions of the industry-standard ENA, includes many easy-to-use features and is optimized for efficient measurements and high reliability.



Features

- S-parameter or T/R test set models
- 50 ohm or 75 ohm system impedance available
- easy to use features for productivity
- optional electronic calibration (ECal) module simplifies and speeds your calibration process

www.agilent.com/find/ena

Fast, Accurate, Multiport and Balanced Measurements

ENA RF network analyzers

E5070B, E5071B

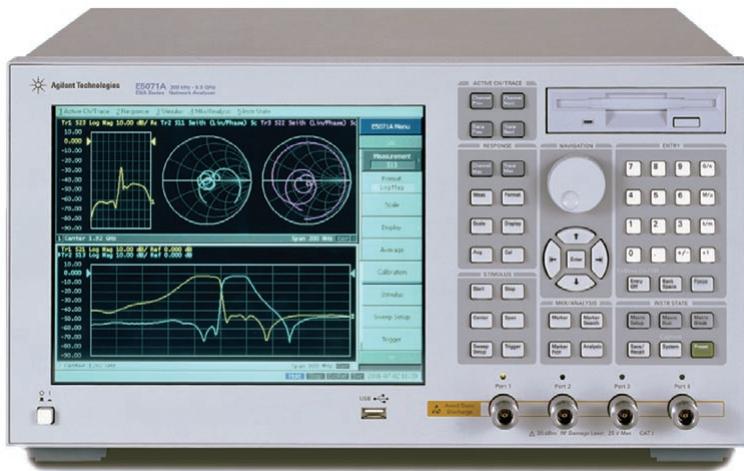
The Agilent ENA offers fast, accurate measurements for multiport components such as duplexers and couplers. Up to four built-in test ports, are available for both the E5070B (3 GHz) and the E5071B (8.5 GHz).

The ENA offers built-in balanced measurement capability, which enables you to test advanced handset components such as balanced SAW filters. It provides mixed-mode S-parameter measurements with a fixture simulator function that includes matching circuit embedding/de-embedding and impedance conversion capabilities.

In addition, the ENA provides frequency-offset mode to characterize your mixers and converters accurately.

Efficient measurements can be easily made in manufacturing. Using the built-in Microsoft® Visual Basic® for Application (VBA) you can quickly develop test routines or automation programs. In addition, the parts-handler interface makes it easy to integrate the ENA into an automation system and enables fast communication.

These integrated measurement capabilities provide the lowest test cost per component and dramatically improve test throughput of multiport and balanced components.



Features

- 2-, 3- or 4-port measurements with full port calibration
- built-in balanced measurement capability
- fixture simulator for balanced component analysis
- frequency-offset mode for mixer measurements
- optional electronic calibration (ECal) module simplifies and speeds your calibration process

www.agilent.com/find/ena

High-Performance, Versatile RF Network Analyzers

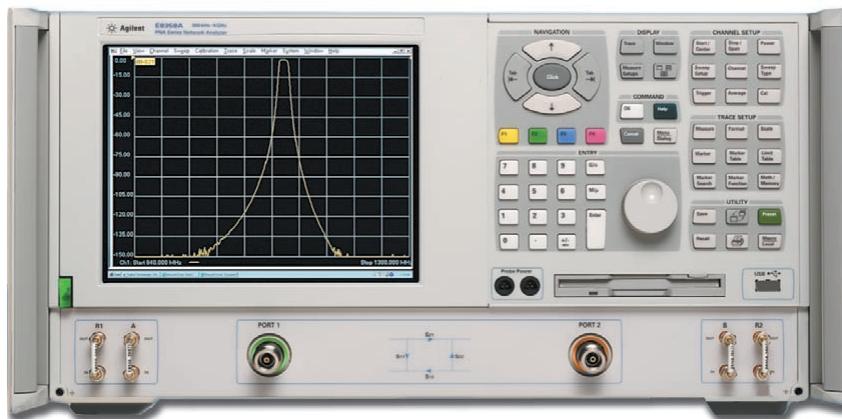
PNA RF network analyzers

E8356/7/8A, E8801/2/3A, N3381/2/3A

Agilent PNA RF network analyzers offer an unsurpassed combination of performance, speed, and outstanding interconnectivity capabilities to meet the challenges of component testing.

The E8356/7/8A are two-port models (3, 6, or 9 GHz) that provide you the highest performance available from Agilent network analyzers. They offer 128 dB dynamic range at the test ports and 143 dB with direct receiver access. They also provide through-reflect-line (TRL)/ line-reflect-match (LRM) calibration capability for in-fixture and on-wafer devices. The configurable test set option enables you to customize the test set signal path. The E8801/2/3A models are also two-port, but offer three receivers and optional functionality, which provides you the opportunity to configure a more economical instrument that meets your needs. The N3381/2/3A are three-port models with full three-port calibration that enable fast, accurate measurements of all nine S-parameters.

The PNA RF series offers several capabilities that can increase your design and test efficiency dramatically. The Windows® operating system provides the possibility of expanding the instrument's connectivity. From the Windows desktop you can install measurement tools, which reduce the need for a dedicated PC. Use on-line help to quickly refer to programming and user documentation. Furthermore, COM/DCOM provides a powerful automation function.



Features

- 143 dB dynamic range with direct receiver access
- 2- or 3-port measurements with full port calibration
- expandability with configurable test set
- advanced connectivity to PC environment

www.agilent.com/find/pna

New Standard for General Purpose Microwave Network Analysis!

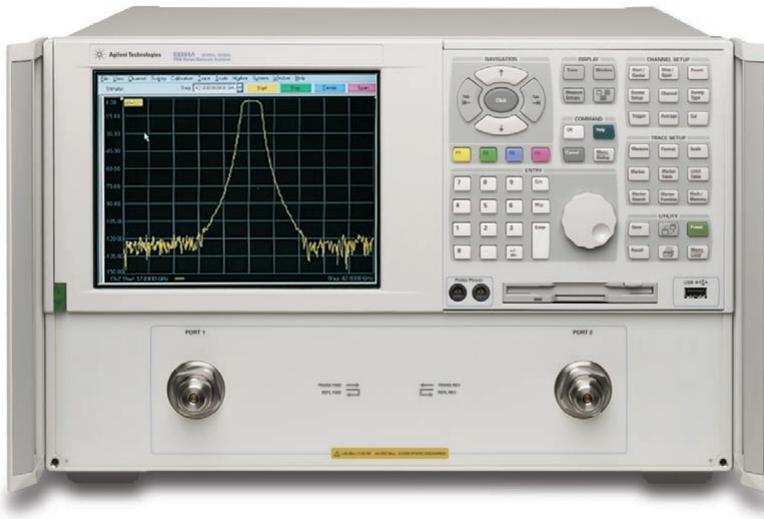
PNA-L microwave (MW) network analyzers

N5230A

The PNA-L is designed for your general-purpose network analysis needs and priced for your budget. Advanced features help you work quickly, easily, and accurately. With the same firmware as the PNA, the PNA-L offers the perfect balance of value and performance.

The PNA-L is available with frequency coverage from 10 MHz to 20, 40, or 50 GHz and offers capabilities that can dramatically increase your design and test efficiency. The Windows operating system provides the ability to expand the instrument's connectivity and provides tools for maximum flexibility. From the Windows desktop you can install measurement tools, which reduce the need for a dedicated PC. Use embedded Help to quickly refer to programming and user documentation from within the instrument. Furthermore, COM/DCOM programming provides a powerful automation environment.

PNA-L provides efficiency and flexibility in both manufacturing and R&D applications for industries ranging from Wireless LAN components to Aerospace & Defense.



Features

- measurement speeds as fast as 9 μ s per point
- superior performance and advanced connectivity compared to our 872x series network analyzers
- optional time-domain and frequency-offset capabilities
- optional electronic calibration (ECal) modules allow you to calibrate 10 times faster than mechanical calibration
- up to 32 independent measurements channels

www.agilent.com/find/pna

High-Performance Microwave Measurements

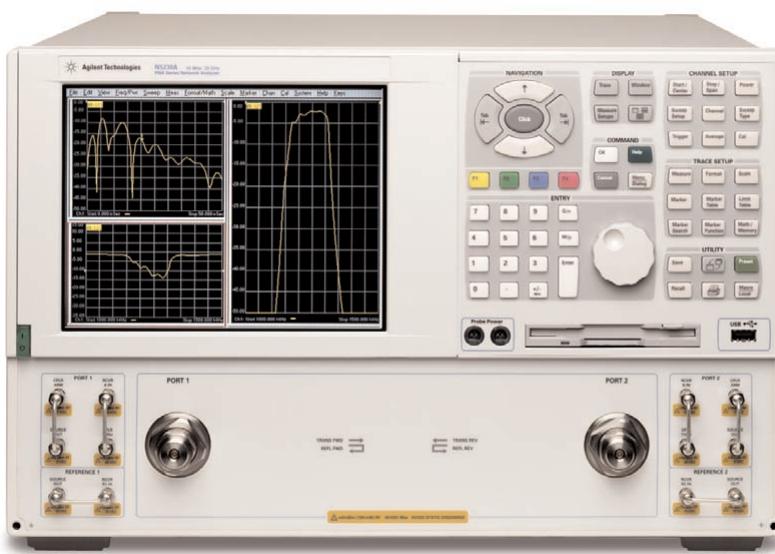
PNA microwave (MW) network analyzer

E8361A, E8362/3/4B

The Agilent E8361A and E8362/3/4B are the microwave frequency models from the PNA series of network analyzers. These models offer an unsurpassed combination of high performance, speed, and outstanding interconnectivity capabilities to meet the challenges of component testing.

The microwave PNA network analyzers cover 10 MHz to 20, 40, 50 and 67 GHz frequency ranges with excellent accuracy. These analyzers are suitable for high-performance microwave devices, such as satellite communication components. They offer 123 dB dynamic range at the test ports and 136 dB with direct receiver access. They also provide TRL/LRM calibration capability for in-fixture and on-wafer devices. In addition, the receiver architecture enables frequency-offset mode to characterize your mixers and converters. The configurable test set allows you to connect external test sets easily and make accurate multiport measurements.

The Windows® operating system provides the ability to expand the instrument's connectivity and provides tools for maximum flexibility. In addition, from the Windows desktop you can install measurement tools, which reduce the need for a dedicated PC, and use on-line Help to quickly refer to programming and user documentation. Furthermore, COM/DCOM provides a powerful automation function. These functions can increase your design and test efficiency dramatically.



Features

- 136 dB dynamic range with direct receiver access
- expandability with configurable test set
- optional advanced mixer and converter test
- optional electronic calibration (ECal) modules allow you to calibrate 10 times faster than mechanical calibration
- optional antenna and pulsed-RF measurements

www.agilent.com/find/pna

110 GHz Benchtop System for High-Performance Millimeter-Wave Measurements

PNA mm-wave network analyzers

N5250A

The Agilent N5250A is the millimeter-wave frequency model of the PNA series of network analyzers. This model offers an unsurpassed combination of high performance, speed, and outstanding interconnectivity to meet the challenges of coaxial and on-wafer device testing to 110 GHz. Banded solutions are also available to cover frequencies up to 325 GHz.

The N5250A allows you to minimize space and maintenance costs with compact test heads and two built-in synthesizers. It provides TRL/LRM calibration capability for in-fixture and on-wafer devices. In addition, optional bias-tees can be added in the combiner assembly very near the device under test, which can greatly improve device stability. The bias-tees have tri-axial connectors for force, sense, and ground. With a single sweep from 10 MHz to 110 GHz, you can maximize your frequency coverage. It offers 123 dB dynamic range at the test ports and can achieve sweep speeds up to 42 times faster than the 8510XF network analyzer.

If you only need a specific band of millimeter-wave frequency coverage, you can customize the most cost-effective solution. This solution consists of a microwave PNA, N5260A test set controller, and banded test heads from Oleson Microwave.



Features

- single sweep from 10 MHz to 110 GHz
- compact test heads and two built-in synthesizers
- 29 IFBW settings, 32 independent channels, 64 traces, and 16,001 points
- optional frequency coverage up to 325 GHz
- Agilent 8510 to PNA code conversion assistant

www.agilent.com/find/pna

Affordable Scalar Network Analyzers

8757 scalar network analyzer

8757D

The Agilent 8757D is a scalar transmission/reflection network analyzer with three or four detector inputs and four independent color display channels, which can process the signals from detectors and directional bridges. The 8757D offers fast measurement speed, limit testing, and external-disk save/recall. AC detection improves measurement accuracy and provides greater than 76 dB dynamic range.

You can combine the 8757D with two external sources and use it to measure conversion loss and compression of mixers. For amplifier testing, in addition to measuring gain, flatness, and return loss, the 8757D can measure 1 dB gain compression with near-power-meter accuracy. For characterizing the power accuracy of the 85037 series precision detectors, you can add an internal power calibrator (Option 8757D-002) to the 8757D.

A complete scalar system includes a 8757D, a swept source, a directional bridge or coupler, and detectors. For higher frequencies, Agilent offers millimeter-wave source modules and waveguide accessories.



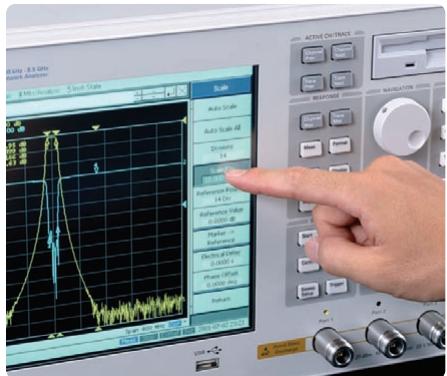
Features

- scalar measurements
- three or four detector inputs
- optional power calibrator

www.agilent.com/find/8757

Measurement Solutions for Your Application

Research and development



Network analysis and more

S-parameter measurements are the most common measurement parameters for network analysis. However, if you only need to measure transmission or reflection characteristics, you might consider a network analyzer with a T/R test set to help manage cost. In some cases, you might want to make additional types of measurements like absolute power, spectrum, impedance, time-domain and pulsed-RF. Time-domain and pulsed-RF measurements are often used for R&D activities to evaluate filters or high-power devices, respectively. Agilent's network analyzers offer a wide range of capabilities - providing you with convenient and cost-effective solutions tailored to your measurement needs.

Connector types and calibration accuracy

In an actual measurement environment, your devices might not have coaxial connectors, such as when you perform on-wafer measurements, or your devices might not have insertable connector types. In either case, it is difficult to perform an accurate calibration, which will affect measurement accuracy. Agilent network analyzers have various calibration functions, such as TRL, adapter-removal calibration, and embedding/de-embedding to ensure measurement accuracy in these types of situations. TRL enables our network analyzers to perform accurate on-wafer or in-fixture measurements. Adapter-removal calibration or our electronic calibration (ECal) modules make it possible to perform calibration for non-insertable co-axial connectors. Embedding/de-embedding allows for the mathematical removal of fixtures. These functions will help you produce accurate measurements.

Expanding your system or using measurement data to write reports

Automation capabilities are critical for making complex component measurements. Internal and external programming capabilities like Visual Basic and Agilent VEE make it easier to develop automation programs and even control other instruments as a system.

Another common, time-consuming task for R&D engineers is incorporating analysis data into simulations and reports. Agilent network analyzers provide linkages to design tools such as Advanced Design System (ADS), that let you simulate and analyze a system without hardware – saving you valuable time and money. In addition, many of our network analyzers are compatible with IntuiLink Connectivity Software, which enables you to easily incorporate measurement results into Microsoft applications.

ADS: www.agilent.com/eesof-eda

VEE: www.agilent.com/find/vee

IntuiLink: www.agilent.com/find/intualink

ECal: www.agilent.com/find/ecal

Measurement Solutions for Your Application

Research and development

Research and development	E5100 series	Combo series	ENA-L series	ENA series	PNA RF series	PNA-L MW series	PNA MW series	PNA mm-wave series	8757 series
Basic measurements									
S-parameters	● ¹	● ¹	●	●	●	●	●	●	
Transmission and reflection with T/R test set	● ¹	● ¹	●						●
Absolute power	●	●		●	●	●	●	● ²	●
Spectrum analyzer function		●							
Impedance analyzer function	●								
Frequency-offset mode			●		●	●	●	●	
Antenna						●			
Non-coaxial devices³									
TRL calibration (on-wafer measurement)				●	●	●	●	●	
Waveguide measurements				●	●	●	●	●	●
Non-insertable devices⁵									
Adapter-removal calibration using mechanical calibration				●	●	●	●	●	
Different connector types supported by ECal			●	●	●	●	●	● ²	
Applications									
Time-domain mode/gating			● ⁴	●	●	●	●	●	
TOI and harmonics						●	●	● ²	
Pulsed-RF testing							● ⁶	● ²	
Frequency conversion application							●	● ²	
Programming and connectivity									
Windows-OS			● ⁷	● ⁷	● ⁸	● ⁸	● ⁸	● ⁸	
LAN interface			●	●	●	●	●	●	
Internal programming capability	●	●	●	●	● ¹⁰	● ¹⁰	● ¹⁰	● ¹⁰	● ¹⁰
ADS linkage				●	●	●	●	●	
VEE linkage		● ¹⁰		●	●	●	●	●	
IntuiLink	●	●	●	●	●	●	●	●	●

1. Requires an external S-parameter test set or T/R test set.

2. Functions up to 67 GHz.

3. For example, on-wafer, in-fixture, or waveguide applications.

4. Time domain gating is not supported.

5. A non-insertable device is a device that cannot be inserted in place of a zero-length through. For example, a device that has the same connectors on both ports (type and sex) or different types of connectors on each port (for example, waveguide on one port and coaxial on the another).

6. Requires Option H08.

7. Closed environment, which does not allow access to a Windows desktop operating system.

8. Open environment, which allows access to a Windows and enables you to install software and manage data for easy post-measurement analysis.

9. Includes Agilent VEE, LabView, C#, Visual Basic, and Visual Basic for Applications.

10. The PNA's open architecture enables you to install any programming software.

11. Available on the 4395A only.

Measurement Solutions for Your Application

Manufacturing test



Optional electronic calibration (ECal) modules for easy, accurate calibration

Unlike the traditional mechanical calibration technique, Agilent's ECal modules only require one set of connections to perform full two-port calibration. Controlled through the front panel USB port, and requiring only one set of connections, ECal drastically simplifies the calibration process for non-technical operators.

An ENA or PNA controls the ECal module to perform the entire calibration, providing:

- Faster calibration and reduced complexity
- Reduced chance of operator error
- Reduced wear on connectors

Sweep and data analysis

Total measurement speed can be divided into several different components such as sweep speed, display processing, data analysis, and data transfer. In low-volume manufacturing, the data analysis and display speeds are unimportant. After the measurement, a limit test or a marker function is typically used. Conversely, in high-volume manufacturing the sweep speed and data analysis speed are important. In many cases, analysis needs to be done quickly using internal programming capability or waveform analysis commands, and the analyzer must send pass/fail results to an automated system. In both cases, the sweep speed can be maximized using segment sweep speed. For automation, you can choose from a variety of Windows-compatible programming environments like VBA, VB or Agilent VEE. In case you want to transfer all data to an external computer quickly, COM/DCOM provides a seamless environment between your instruments and external computers.

Communication interfaces

It is becoming more common to have a LAN interface in test and measurement instruments. A LAN is convenient to send data from your manufacturing line to your office, or to monitor measurement status, or have a central data server, or use network printers.

For high-volume automation applications, fast communication with an automated handler system is important. A parts handler interface is commonly used for this purpose. It has a dedicated pin assignment in the I/O interface so that triggers measurement-end status, and limit-test results are communicated quickly between the instrument and the automated handler system.

Measurement Solutions for Your Application

Manufacturing test

Manufacturing test	E5100 series	Combo series	ENA-L series	ENA series	PNA RF series	PNA-L MW series	PNA MW series	PNA mm-wave series	8757 series
Programming									
Internal programming capability ¹	●	●	●	●	● ²	● ²	● ²	● ²	
Fast data transfer ³			●	●	●	●	●	●	●
Calibration									
Adapter-removal calibration ⁴				●	●	●	●	●	●
ECal support			●	●	●	●	●	●	● ⁵
Measurement and analysis									
Segment sweep ⁶	●	●	●	●	●	●	●	●	
Pass/fail testing	●	●	●	●	●	●	●	●	●
Embedding and de-embedding ⁷				●	●	●	●	●	●
Waveform analysis command ⁸	●		●	●					
Interface									
LAN			●	●	●	●	●	●	
I/O port	●	●	●	●	●	●	●	●	
Parts handler interface ⁹	●	●	●	●	●	●	●	●	
VGA output	●	●	●	●	●	●	●	●	●

1. Includes Visual Basic, and Visual Basic for Applications.

2. The PNA's open architecture enables you to install any programming software.

3. COM/DCOM provides faster data transfer than GPIB.

4. The calibration technique used for non-insertable devices such as those with the same connectors on input and output ports.

5. Functions up to 67 GHz.

6. Segment sweep includes sweep types that are known as list and fast-swept list.

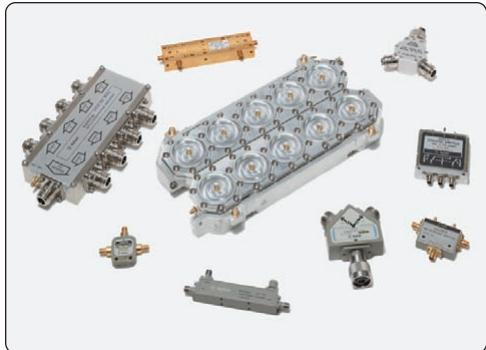
7. Functions to embed or de-embed a fixture's characteristics.

8. Programming commands to quickly retrieve parameters of filters and resonators.

9. The parts handler interface is an I/O-port specialized for communication with an automatic parts handler system.

Measurement Solutions for Your Application

Filter and duplexer measurements



Dynamic range, IF bandwidth and sweep time

Dynamic range requirements vary among applications. Agilent offers a variety of network analyzers with different dynamic ranges, so you can choose the best one for your application. For wide dynamic range, Agilent's RF PNA series network analyzers are a good choice. The PNA series offers 128 dB dynamic range at test port and 143 dB with direct receiver access. In addition, many analyzers offer segment sweep – a convenient function that manages dynamic range and sweep speed. This function enables you to set different IFBWs for the pass band or rejection band, and the sweep speed can be optimized for your measurement needs.

Calibration for filter testing

Agilent network analyzers provide various functions that help you perform efficient, accurate filter evaluations, which can help shorten your design cycles. For instance, the adapter removal calibration functions make it possible to accurately calibrate non-insertable devices. Interpolated calibration is convenient if the measurement frequency is unknown.

Time domain, multiport, and balanced measurement capabilities for advanced devices

Today's wireless devices require test instruments that have advanced measurement functionality. For example, a time-domain function is needed to easily tune coupled-cavity-resonator bandbass filters. Duplexer or front-end modules for handsets often require multiport and balanced measurement capabilities. For more details on multiport and balanced testing, see page 19.

Measurement Solutions for Your Application

Filter and duplexer measurements

Filter and duplexer measurements	E5100 series	Combo series	ENA-L series	ENA series	PNA RF series	PNA-L MW series	PNA MW series	PNA mm-wave series	8757 series
Dynamic range									
Wide dynamic range ¹	●	●		●	●	●	●	●	
Direct receiver access to obtain widest possible dynamic range					●	●	●	●	●
Calibration									
Adapter removal calibration				●	●	●	●	●	●
Interpolated calibration	●	●	●	●	●	●	●	●	●
Measurement and analysis									
Segment sweep ²	●	●	●	●	●	●	●	●	
Four-parameter display	●	●	●	●	●	●	●	●	
Marker statistics function ³	●	●	●	●	●	●	●	●	●
Other functions									
Time domain measurement			● ⁴	●	●	●	●	●	●
Filter tuning software				● ⁵	●	●	●	●	●
Balanced measurement capability ⁶				●	● ⁷	● ⁷	● ⁷	● ⁷	
Multi-port measurement capability ⁶			● ⁷	●	● ⁷	● ⁷	● ⁷	● ⁷	

1. Wide dynamic range is defined as greater than 120 dB for RF analyzers and greater than 90 dB for microwave analyzers.

2. Segment sweep includes sweep types that are known as list and fast swept list.

3. Obtains real-time calculations of device characteristics such as maximum/minimum, center frequency, and 3 dB bandwidth.

4. Time gating is not supported.

5. Requires an external PC.

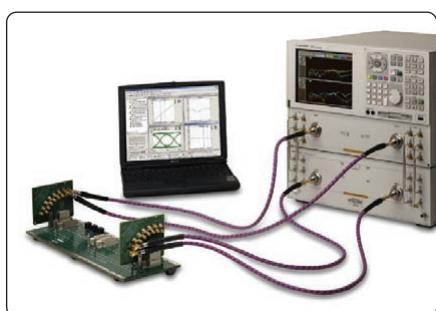
6. For more details about balanced and multi-port tests, see page 20.

7. Balanced measurement capability requires an external test set and software.

8. An external test set may be required to achieve these functionalities.

Measurement Solutions for Your Application

Multiport and balanced testing



Balanced measurement solutions for RF and microwave frequencies

ENA E5070B/1B ENA network analyzer with E5091A multiport test set
N1953/5/7B physical layer test system

The ENA network analyzer series provides a high-speed, integrated balanced measurement solution up to 8.5 GHz. If you require higher frequency coverage, the N1900B series Physical Layer Test System (PLTS) will meet your needs. PLTS solutions combine a vector network analyzer (VNA) with an S-parameter test set and Windows-based software for balanced measurements up to 50 GHz.

Multiport testing for communication components

Many modern components have more than two ports. In order to test these devices efficiently, network analyzers with multiple ports are required. Agilent offers numerous multiport instruments for you to choose from. One example is the Agilent ENA series. The ENA has built-in three- or four-port measurement capability – enabling fast and accurate multiport measurements.

Calibration for multiport measurements

When doing multiport measurements, you need to use the proper calibration method to achieve accurate measurements. Agilent offers a three- or four-port, full calibration function together with multiport measurement capability. Four-port ECal modules are available as well, so that calibration can be done easily and quickly. When it is not possible to place coaxial connectors on your design, Agilent PLTS systems provide TRL and LRM calibration techniques to ensure accuracy for balanced, on-wafer measurements.

Balanced measurements for balanced components

Balanced components are commonly used in communications devices to maintain RF signal quality. The ENA series has a built-in balanced capability to make fast and easy balanced measurements. It also has a fixture simulation function, including matching circuit embedding/de-embedding and impedance conversion capabilities.

Multiport testing for CATV components

Many CATV components, including taps, dividers, and distribution amplifiers, have multiple ports. Network analyzers with multiport test sets drastically increase the test efficiency of these components. The ENA-L network analyzer with the 87075C 75 ohm multiport test set is specifically designed for testing multiport CATV components.

External test set for multiport and balanced testing

In order to expand flexibility and capability, Agilent also offers multiport and balanced measurement solutions that use external test sets. For example, several multiport test sets and the N1900B Physical Layer Test System can be used with the PNA series network analyzers. For details, visit www.agilent.com/find/multiport

Measurement Solutions for Your Application

Multiport and balanced testing

Multiport and balanced devices	E5100 series	Combo series	ENA-L series	ENA series	PNA RF series	PNA-L MW series	PNA MW series	PNA mm-wave series	8757 series
Multiport measurements									
Built-in 4-port measurement capability				●					
Built-in 3-port measurement capability				●	●				
Multiport measurement capability with external test set ¹			●	●	●	●	●	●	
Multiport calibration									
Full 4-port calibration				●	● ²	● ²	● ²		
Full 3-port calibration				●	●				
Balanced measurement									
Built-in balanced measurement capability				●					
Balanced measurement capability with external test set ³					●		●		
Fixture simulation/embedding and de-embedding				●	●	●	●	●	

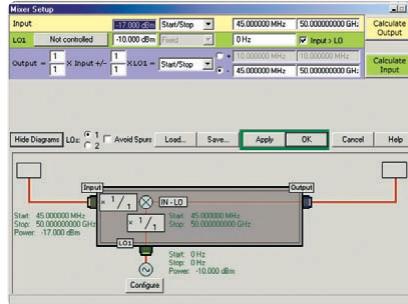
1. Agilent 87050A/E, 87075C, Z5621A, E5091A, and N4419/20/21B are available as external multiport test sets. Refer to Test Solutions for Multiport and Balanced Devices brochure (literature number 5988-2461EN available on the www.agilent.com/find/pna Web site) for more details.

2. Available only when used with external test sets and software.

3. The external test set and software are provided in the Agilent N1900B Series Physical Layer Test System. For more details, refer to the Agilent Physical Layer Test Systems Data Sheet (literature number 5988-5288EN) available on the PLTS Web site: www.agilent.com/find/plts

Measurement Solutions for Your Application

Mixer and amplifier measurements



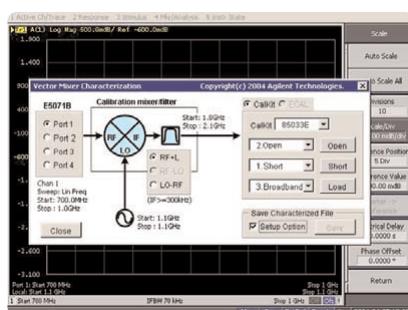
The PNA Frequency Converter Application simplifies setup and calibration for advanced mixer measurements such as absolute phase and group delay.

Mixer measurements

Frequency-translation devices such as mixers, converters, and tuners are critical components in most RF and microwave communication systems. They present unique measurement challenges because their input and output frequencies are different. Network analyzers used for testing these devices need to have an frequency-offset mode to detect output frequencies different from the input.

The PNA microwave and mm-wave series offer the Frequency Converter Application (FCA), an easy-to-use graphical user interface and advanced calibration technique. The FCA automates the measurement process, making it possible for users without extensive knowledge of mixer measurements to set up, calibrate, and characterize devices quickly and accurately.

The ENA offers the frequency-offset mode (FOM) that provides frequency-offset sweep, external signal source control, and fixed IF/RF measurement capabilities. The ENA FOM option supports both scalar-and vector-mixer calibrations with inherited mixer measurement techniques from the microwave PNA. These measurement techniques are key to making extremely accurate measurements. Also, this option provides harmonics measurement capabilities for non-linear devices such as amplifiers, semiconductor switches, and front-end modules.



The ENA Frequency-Offset Mode offers vector mixer calibration technique that enables you to perform accurate absolute group delay measurements for frequency-translating devices.

Amplifier measurements

Agilent network analyzers easily measure commonly specified amplifier parameters like gain, gain compression, isolation, return loss, and group delay. The power sweep function is often required to make amplifier measurements, and harmonic distortion is commonly used to understand the amplifier's non-linear behavior. Additional amplifier information and detailed application notes are available on our PNA Series Web site: www.agilent.com/find/pna

Power meter calibration

For both mixer and amplifier testing, power meter calibration provides leveled absolute power to devices that are sensitive to absolute input or output levels. This function automatically controls power meters to set the power anywhere in the test setup with power meter accuracy, or to calibrate the network analyzer's receivers for accurate absolute-power measurements.

Measurement Solutions for Your Application

Mixer and amplifier measurements

Mixer measurements	E5100 series	Combo series	ENA-L series	ENA series	PNA RF series	PNL-L MW series	PNA MW series	PNA mm-wave series	8757 series
Measurement and analysis									
Magnitude measurement ²				●		●	●	●	●
Phase measurement						●	●		
Relative phase						●	●	●	
Absolute phase				●			●	● ³	
Power sweep				● ¹	●	●	●	● ³	●
Internal control of multiple sources						●	●	●	
Calibration									
Power meter calibration ⁴				● ⁵		●	●	● ³	
Amplifier measurements									
Measurement and analysis									
Power sweep	●	●	●	●	●	●	●	● ³	●
Log sweep		●	●	●	●	●	●	●	
Internal bias-tee					●		●		●
High-power measurements	●	●			●	●	●		
Four-parameter display	●	●	●	●	●	●	●	●	●
Direct receiver access to connect customer-provided high-power test set	●	●			●	●	●	●	
Frequency-offset mode				●		●	●	●	●
Calibration									
Power meter calibration ⁴				● ⁵	●	●	●	● ³	●

1. ENA supports one signal source.

2. Frequency-offset modes of the 8753, 8720, ENA and PNA series let the source and receiver operate at different frequencies.

Both magnitude and phase measurements can be made.

3. Functions up to 67 GHz.

4. Transfers the accuracy of the power meter to the network analyzer, providing very accurate absolute power measurements.

5. Source power meter calibration only.

Related Network Analyzer Products

Electronic calibration (ECal) modules

ECal is a precision, single-connection calibration technique for 2- or 4-port Agilent vector network analyzers. Agilent ECal modules are fully traceable and verifiable against electronic impedance standards and can simplify your daily calibration routine. ECal modules are available for Type N-50, N-75, 7 mm, 3.5 mm, Type F, and 7-16 (300 kHz to 9 GHz) connectors. Modules are available in microwave frequency ranging from 10 MHz to 67 GHz for 7 mm, Type N-50, 3.5 mm, 2.92 mm, 2.4 mm and 1.85 mm. Both 2-port (RF and microwave) and 4-port (RF only) modules are available.

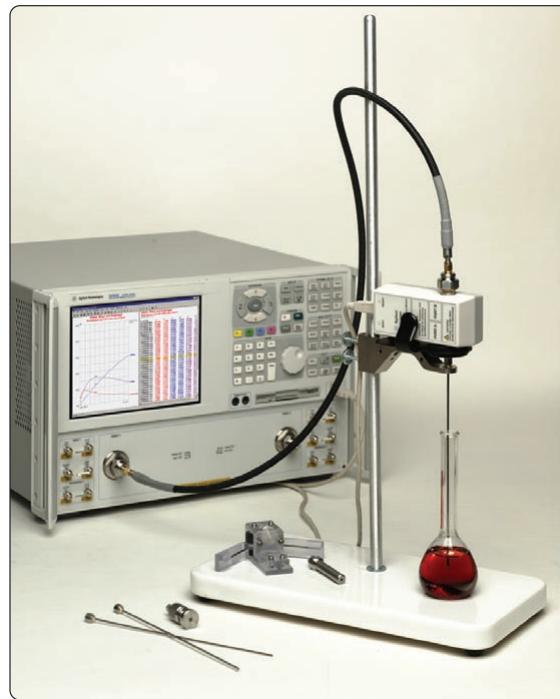


www.agilent.com/find/ecal

85070E Dielectric Probe Kit and 85071E Materials Measurement Software

The Dielectric Probe Kit and Materials Measurement Software convert S-parameter network analyzer measurements to complex permittivity and permeability. A friendly graphical user interface sets up the measurements and results are displayed in seconds.

Complex permittivity and permeability are determined by a material's molecular structure, so they can be related to other properties of interest as well. Measuring them can provide critical insight to applications in many industries. It can be useful in all stages of a product's lifecycle: design, incoming inspection, process monitoring, and quality assurance. For example, it is useful for improving ferrite, radome, and absorber designs. It can provide important information about materials used in state-of-the-art RF and microwave electronic components. Even biomass, bulk density, bacterial content, and chemical concentration can be related to a material's electromagnetic properties. Let Agilent Technologies materials measurement products provide critical insight into your application!



www.agilent.com/find/materials

N1900B Series Physical Layer Test Systems (PLTS)

Agilent's PLTS solutions provide the highest accuracy and most comprehensive tool set for model extraction and characterization of single-ended and differential physical-layer interconnects, or balanced RF and microwave components with frequency coverage up to 50 GHz. These test solutions offer single-ended, balanced, and mixed-mode measurements in both frequency and time domain, eye-diagram analysis, and RLCG transmission-line parameter extraction.



www.agilent.com/find/plts

Specification and Feature Comparison

RF network analyzers

	E5100 series	Combination analyzer series
Model number	E5100A 	4395A 4396B 
Frequency range	E5100A: 10 kHz to 180 MHz/300 MHz	4395A: 10 Hz to 500 MHz 4396B: 100 kHz to 1.8 GHz
Number of ports¹	2	2
Balanced measurements¹	no	no
System impedance	50 ohm	50 or 75 ohms
System dynamic range	120 dB	4395A: 115 dB 4396B: 120 dB
Power at test port	–48 dBm to +22 dBm(Opt.001 and 010) –65 dBm to +5 dBm (at RF OUT 2 with Option 600)	4395A: –50 to +15 dBm 4396B: –60 to +20 dBm
Power sweep range	70 dB (Power Opt. 010)	20 dB
Sweep type	linear, segment ² , power	linear, log, segment ² , power
Error correction		
Full 2-port	no	yes
Full 3 or 4-port	no	no
TRL	no	no
Adapter-removal	no	no
ECal support	no	no
Measurement channels	2	2
Maximum number of data traces	4	4
Windows-OS	no	no
Internal automation	IBASIC	IBASIC
I/O	GPIB, VGA, parallel, mini-DIN	GPIB, VGA, parallel, mini-DIN
ADS linkage	no	no
Built-in source attenuator	yes (with Option 801/2/3)	no
DC bias input	no	no
Time domain	no	no
Corrected specifications³	do not specify system performance	do not specify system performance
Trace noise	0.01 dB rms (1 kHz IFBW)	4395A: 0.005 dB rms (300 Hz IFBW) 4396B: 0.002 dB rms (300 Hz IFBW)
Measurement speed⁴ (1 sweep, 201 points)	8 ms (1-port cal, ramp-sweep) 64 ms (1-port cal, step-sweep)	165 ms (response cal, gain, 30 kHz BW) 215 ms (response cal, gain and phase, 30 kHz BW)

1. Table shows the capabilities of the stand-alone instrument. Possible to add capabilities with external test sets. See page 19.

2. Segment includes sweep types that are known as list and fast swept list.

3. Dir = directivity; SM = source match; LM = load match; Refl trk= reflection tracking; Trans trk = transmission tracking

4. Includes system retrace time, but does not include source bandswitch times. Refer to product data sheets for detailed measurement conditions.

Specification and Feature Comparison

RF network analyzers

	ENA-L RF series	ENA RF series	PNA RF series
Model number	E5061A E5062A	E5070B E5071B	E8356/7/8A E8801/2/3A N3381/2/3A
Frequency range	E5061A: 300 kHz to 1.5 GHz E5062A: 300 kHz to 3 GHz	E5070B: 300 kHz to 3 GHz E5071B: 300 kHz to 8.5 GHz	E8356A/E8801A/N3381A: 300 kHz to 3 GHz E8357A/E8802A/N3382A: 300 kHz to 6 GHz E8358A/E8803A/N3383A: 300 kHz to 9 GHz
Number of ports¹	2	2, 3 or 4	2 or 3
Balanced measurements¹	no	yes	no
System impedance	50 ohms or 75 ohms	50 ohms	50 ohms
System dynamic range	115 dB	120 dB (to 1.5 GHz) 122 dB (to 4 GHz) 118 dB (to 6 GHz) 113 dB (to 7.5 GHz) 106 dB (to 8.5 GHz)	123 dB (to 1 MHz) 128 dB (to 3 GHz) 118 dB (to 6 GHz) 113 dB (to 9 GHz) (Direct receiver access increases dynamic range 15 dB in each frequency range)
Power at test port	–5 to +10 dBm –45 to +10 dBm (Option 1E1, 250 or 275)	–50 dBm to +10 dBm	–85 dBm to +10 dBm Available with E8356/7/8A (Opt. UNL)
Power sweep range	15 dB	25 dB	20 to 25 dB
Sweep type	linear, log, segment ² , power, CWV	linear, log, segment ² , power, CWV	linear, log, segment ² , power, CWV
Error correction	Full 2-port Full 3 or 4-port TRL Adapter-removal ECal support	yes (S-parameter test sets only) no no no yes	yes yes yes yes yes
Measurement channels	4	16	32 ³
Maximum number of data traces	16	81	64
Windows-OS	yes (Closed) ⁴	yes (Closed) ⁴	yes (Open) ⁵
Internal automation	VBA, SCPI, COM	VBA, SCPI, COM	SCPI, COM/DCOM ⁶
I/O	LAN, USB, GPIB, VGA, parallel, handler, mini-DIN	LAN, USB, GPIB, VGA, parallel, handler, mini-DIN	LAN, USB, GPIB, VGA, parallel, handler, RS-232
ADS linkage	no	File format supported	Software driver supported
Built-in source attenuator	yes (ES: standard, ET: option)	yes (with option)	yes (E835xA: standard, other models: option)
DC bias input	no	no	yes
Time domain (with Option 100)	yes ⁷	yes (with Opt. 010)	yes (with Opt. 010)
Corrected specifications¹	(type-N, 50 ohms, 2-port cal) Dir 46 to 49 dB SM 40 to 41 dB LM 46 to 49 dB Refl trk ± 0.011 to ± 0.021 dB Trans trk ± 0.015 to ± 0.018 dB	(2-port cal, type-N, 50 ohms) Dir 47 to 52 dB SM 36 to 45 dB LM 39 to 47 dB Refl trk ± 0.040 to 0.070 dB Trans trk ± 0.039 to 0.136 dB	(2-port cal, type-N, 50 ohms, E835xA model) Dir 47 to 54 dB SM 36 to 45 dB LM 39 to 47 dB Refl trk ± 0.040 to ± 0.070 dB Trans trk ± 0.039 to ± 0.135 dB
Trace noise	0.005 dB rms @ 3 kHz IFBW ≥ 1 MHz	0.001 dB rms (3 MHz to 4.25 GHz) (3 kHz BW)	0.002 dB rms (1 kHz BW)
Measurement speed (1 sweep, 201 points)	35 ms (2-port cal, 30 kHz BW)	8 ms (2-port cal) (100 kHz BW)	29 ms (2-port cal) (35 kHz BW)

1. Includes system retrace time, but does not include source bandswitch times. Refer to product data sheets for detailed measurement conditions.

2. Segment includes sweep types that are known as list and fast swept list.

3. For E8356/7/8A, these functions are available with firmware revision A.02.50 or later.

4. The ENA series does not allow you to access a Windows desktop operating system.

5. The PNA's open architecture allows you to access the operation system and install software, such as Visual Basic.

6. DCOM enables you to have a seamless programming environment between the instrument and a PC.

7. Time domain gating is not supported.

Specification and Feature Comparison

Microwave network analyzers

	PNA-L MW series	PNA MW series	8757 series	PNA mm-wave series
Model numbers	N5230A 	E8362B E8363B E8364B E8361A 	8757D 	N5250A 
Frequency range	10 MHz to 20 GHz (Option 220, 225) 10 MHz to 40 GHz (Option 420, 425) 10 MHz to 50 GHz (Option 520, 525)	E8362B 10 MHz to 20 GHz E8363B 10 MHz to 40 GHz E8364B 10 MHz to 50 GHz E8361A ¹ 10 MHz to 67 GHz	10 MHz to 110 GHz, depends on configuration	10 MHz to 110 GHz, depends on configuration
Number of ports ²	2	2	2	2
Balanced measurements ²	no	no	no	no
System impedance	50 ohms	50 ohm	50 ohms	50 ohms
System dynamic range (at 20 GHz)	108 dB (Option 220, 225) depends on configuration	94 to 125 dB (max. 136 dB with direct receiver access)	75 dB/70 dB (AC/DC detection modes)	111 dB
Power at test port (at 20 GHz)	-27 to +3 dB (Option 220, 225) depends on configuration (60 dB source attenuator option expands min. power to -82 dBm at 10 GHz)	-25 to +5 dBm at 10 GHz (60 dB source attenuator option expands min. power to -82 dBm at 10 GHz)	depends on signal source: +10 or +17 dBm (to 26.5 GHz) +6 dBm (to 40 GHz)	-5 dBm
Power sweep range	25 dB	31 dB	25 dB	20 dB ³
Sweep type	linear, log CW, power, CW, segment	linear, log CW, power, segment	linear, power, CW	linear, log CW, power, segment
Error correction				
Full 2-port	yes	yes	no	yes
TRL	yes	yes	no	yes
Adapter-removal	yes	yes	no	yes
ECal support	yes	yes	no	yes ³
Measurement channels	32	32	2	32
Maximum number of data traces	64	64	4	64
Windows-OS	yes ⁴	yes ⁴	no	yes ⁴
Internal automation	SCPI, D/COM ⁴	SCPI, D/COM ⁴	no	SCPI, COM/DCOM
I/O	LAN, USB ⁵ , GPIB, VGA, parallel, RS-232	LAN, USB ⁵ , GPIB, VGA, parallel, RS-232	GPIB, VGA	LAN, USB ⁵ , GPIB, VGA, parallel, RS-232
ADS linkage	Software driver supported	Software driver supported	no	Software driver supported
Built-in source attenuator	yes (with Option x25)	yes (with Option UNL)	no	yes
DC bias input	no	yes (with Option UNL)	no	yes
Time domain	yes (with Option 010)	yes (with Option 010)	no	yes (with Option 010)
Corrected	(2-port cal, 3.5 mm), 20 GHz models only 44 to 48 31 to 40 44 to 48 ±.003 to .006 ±.010 to .104	(2-port cal, 2.4 mm) Dir 36 to 42 dB SM 31 to 41 dB LM 35 to 42 dB Refl trk ± 0.001 to 0.027 dB Trans trk ± 0.014 to 0.200 dB	(coaxial) Dir 40 dB SM source dependent LM 20 dB	--
Trace noise	0.006 dB rms, 1 kHz BW (at 20 GHz)	0.006 dB rms (1 kHz BW)	unspecified	--
Measurement speed (1 sweep, 201 points correction off)	9 ms (250 kHz BW)	12 ms (35 kHz BW)	--	--

1. Specified to 67 GHz, with operation to 70 GHz.

2. Table shows the capabilities of a stand-alone instrument. Possible to add capabilities with external test set. See page 20.

3. Functions up to 67 GHz.

4. Open Windows environment. You can load any software on the instrument, such as Visual Basic.

5. Keyboard and mouse can be attached using USB ports.

6. Dir = directivity; SM = source match; LM = load match; Refl trk= reflection tracking; Trans trk = transmission tracking

Literature

Our product and application literature is available for viewing and download from our product Web sites listed under "Web Resources" on the back page of this selection guide.

Brochures

Test Solutions for Multiport and Balanced Devices
literature number 5988-2461EN

E5100A Network Analyzer (10 kHz to 180/300 MHz)
literature number 5968-1873E

*Combination Analyzers
(Network/Spectrum/Impedance Analyzers)*
literature number 5965-9374E

ENA-L RF Network Analyzers (300 kHz to 1.5 or 3 GHz)
literature number 5989-0167EN

ENA RF Network Analyzers (300 kHz to 3 or 8.5 GHz)
literature number 5988-3765EN

*PNA-L MW Network Analyzers
(10 MHz to 20, 40, 50 or 67 GHz)*
literature number 5989-0168EN

*MW & RF PNA Network Analyzers
(300 kHz to 20, 40, 50, or 67 GHz)*
literature number 5968-8472E

*N5250A Millimeter-Wave PNA Network Analyzers
(10 MHz to 110 GHz)*
literature number 5988-9620EN.pdf

Signal Integrity Solutions
literature number 5988-5405EN

Application Notes

Amplifiers -
How to Characterize CATV amplifiers effectively
literature number 5965-9434E

Amplifier Linear and Gain Measurements
literature number 5988-8644EN

Amplifier Swept-Harmonic Measurements
literature number 5988-9473EN

Amplifier Intermodulation-Distortion Measurements
literature number 5988-9474EN

*Characterizing Differential Amplifiers with True
Differential Signals*
literature number 5988-9463EN

Mixers/Converters -

*Mixer Conversion-Loss and Group Delay
Measurement Techniques and Comparisons*
literature number 5988-9619EN

*Measuring Absolute Group Delay of Multistage
Converters using PNA Network Analyzers*
literature number 5989-0219EN

*Mixer Transmission Measurements
Using The Frequency Converter*
literature number 5988-8642EN

*Novel Method for Vector Mixer Characterization
and Mixer Test System Vector Error Correction*
literature number 5988-7826EN

Pulsed Measurements -
Accurate Pulsed Measurements
literature number 5989-0563EN

*Pulsed Antenna Measurements
Using PNA Network Analyzer*
literature number 5989-0221EN

Antenna and RCS Measurement Configurations
literature number 5989-0220EN

*Triggering the PNA Series Network Analyzer
for Antenna Measurements*
literature number 5988-9518EN

Additional ENA Application Notes

*On-Wafer Impedance Measurements Using the ENA
and Impedance Parameter Display Software*
literature number 5989-0033EN

*Differential S-parameter Measurements of PCI Express
Connectors using the ENA Series Network Analyzer*
literature number 5988-9848EN

*High Speed fT vs. Ic characterization of
Bipolar transistor Using an ENA Network Analyzer*
literature number 5988-9994EN

*In-Fixture Characterization Using the ENA Series
RF Network Analyzer with Cascade Microtech
Probing System*
literature number 5988-6552EN

*Evolution of Test Automation Using the Built-In VBA
with the ENA Series RF Network Analyzers*
literature number 5988-6192EN

ADSL Copper Loop Measurements
literature number 5968-1196E

Web Resources

Visit our Web sites for additional product information and literature.

Microwave and RF network analyzers:
www.agilent.com/find/na

ENA RF series network analyzers:
www.agilent.com/find/ena

PNA Microwave series network analyzers:
www.agilent.com/find/pna

Electronic calibration (ECal):
www.agilent.com/find/ecal

Materials measurement solutions:
www.agilent.com/find/materials

Physical layer test systems
and signal integrity solutions:
www.agilent.com/find/plts

Test and measurement accessories:
www.agilent.com/find/accessories

Mixers and converters:
www.agilent.com/find/fca



Agilent Email Updates

www.agilent.com/find/emailupdates

Get the latest information on the products and applications you select.

Agilent Technologies' Test and Measurement Support, Services, and Assistance

Agilent Technologies aims to maximize the value you receive, while minimizing your risk and problems. We strive to ensure that you get the test and measurement capabilities you paid for and obtain the support you need. Our extensive support resources and services can help you choose the right Agilent products for your applications and apply them successfully. Every instrument and system we sell has a global warranty. Support is available for at least five years beyond the production life of the product. Two concepts underlie Agilent's overall support policy: "Our Promise" and "Your Advantage."

Our Promise

Our Promise means your Agilent test and measurement equipment will meet its advertised performance and functionality. When you are choosing new equipment, we will help you with product information, including realistic performance specifications and practical recommendations from experienced test engineers. When you use Agilent equipment, we can verify that it works properly, help with product operation, and provide basic measurement assistance for the use of specified capabilities, at no extra cost upon request. Many self-help tools are available.

Your Advantage

Your Advantage means that Agilent offers a wide range of additional expert test and measurement services, which you can purchase according to your unique technical and business needs. Solve problems efficiently and gain a competitive edge by contracting with us for calibration, extra-cost upgrades, out-of-warranty repairs, and onsite education and training, as well as design, system integration, project management, and other professional engineering services. Experienced Agilent engineers and technicians worldwide can help you maximize your productivity, optimize the return on investment of your Agilent instruments and systems, and obtain dependable measurement accuracy for the life of those products.

Agilent T&M Software and Connectivity

Agilent's Test and Measurement software and connectivity products, solutions and developer network allows you to take time out of connecting your instruments to your computer with tools based on PC standards, so you can focus on your tasks, not on your connections. Visit www.agilent.com/find/connectivity for more information.

By internet, phone, or fax, get assistance with all your test & measurement needs

Phone or Fax

United States:

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(fax) (82 2) 2004 5115

Canada:

(tel) 877 894 4414

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China:

(tel) 800 810 0189

(fax) 800 820 2816

Europe:

(tel) (31 20) 547 2323

(fax) (31 20) 547 2390

Japan:

(tel) (81) 426 56 7832

(fax) (81) 426 56 7840

Korea:

(tel) (82 2) 2004 5004

(fax) (82 2) 2004 5115

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(tel) (305) 269 7500

(fax) (305) 269 7599

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Online Assistance:

www.agilent.com/find/assist

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